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|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/043,237 | | Applicant(s)/Patent Under Reexamination DOUMAE, YASUHIRO | |
| | Examiner William C. Vesperman | | Art Unit 2813 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-5,837,588 | 11-1998 | Wu, Shye-Lin | 438/305 |
| * | B | US-5,409,848 | 04-1995 | Han et al. | 438/302 |
| * | C | US-2002/0068395 | 06-2002 | Tran et al. | 438/194 |
| * | D | US-6,352,885 | 03-2002 | Wieczorek et al. | 438/197 |
| * | E | US-6,087,706 | 07-2000 | Dawson et al. | 257/520 |
| * | F | US-2003/0075806 | 04-2003 | Reber, Douglas M. | 257/773 |
| * | G | US-5,869,378 | 02-1999 | Michael, Mark W. | 438/305 |
| * | H | US-4,198,250 | 04-1980 | Jecmen, Robert M. | 438/301 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| * | U | "A Novel Self-aligned Gate-overlapped LDD Poly-Si TFT with High Reliability and Performance", published in the IEEE in 1977 and authored by Mutsuko Hatano, Hajime Akimoto and Takeshi Sakai. |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.